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### IN THE CLAIMS

1. (Withdrawn) A system for incremental statistical timing analysis of an electrical circuit comprising:
  - a. a results input for receiving one or more results of a first statistical timing analysis;
  - b. a change input for receiving one or more changes to the electrical circuit;
  - c. a query input for receiving one or more statistical timing queries that request updated statistical timing information about the electrical circuit; and
  - d. an incremental statistical timing process that provides the one or more answers to the respective queries as an output of the system, the answer being the requested statistical timing information for the electrical circuit with the changes.
2. (Withdrawn) A system, as in claim 1, where the query is one or more of: a statistical arrival time at a node, a statistical required arrival time at a node, a statistical slack at a node, a statistical slew at a node, an arrival tightness probability of an edge, a required arrival tightness probability of an edge, a criticality probability of an edge, a criticality probability of a node, and a probability of a timing test being met.
3. (Withdrawn) A system, as in claim 2, where the query requests one or more of the following: a mean, a variance, an independent random part, a sensitivity to a source of variation, a confidence level, and an entire probability distribution of a statistical timing quantity.
4. (Withdrawn) A system, as in claim 1, where the query requests a criticality of one or more paths through the electrical circuit.

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5. (Withdrawn) A system, as in claim 1, where the query requests a listing of one or more paths through the electrical circuit with the highest probability of being critical.
6. (Withdrawn) A system, as in claim 1, where the query requests a listing of a required number of paths through the electrical circuit in order of criticality probability.
7. (Withdrawn) A system, as in claim 1, where the query requests a listing of one or more critical paths through the electrical circuit in order of criticality probability until the sum of the criticality probabilities exceeds a required probability threshold.
8. (Withdrawn) A system, as in claim 2, where the query requests one or more of: a late mode statistical timing quantity, an early mode statistical timing quantity, a rising statistical timing quantity, and a falling statistical timing quantity.
9. (Withdrawn) A system, as in claim 1, where the change is one or more of: a removal of a wire, an addition of a wire, a buffering of a wire, a removal of a gate, an addition of a gate, a removal of a latch, an addition of a latch, a removal of a clock phase, an addition of a clock phase, and a change in the operating conditions under which timing is performed.
10. (Withdrawn) A system, as in claim 9, in which a change to the electrical circuit is the undoing of the previous change to the electrical circuit.
11. (Withdrawn) A system, as in claim 1, where the electrical circuit is one of a combinational circuit and a sequential circuit.

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12. (Withdrawn) A system, as in claim 1, where the electrical circuit contains one or more of:  
a master-slave latch, a transparent latch, a dynamic circuit, and a flip-flop.
13. (Withdrawn) A system, as in claim 1, where the electrical circuit has multiple clock  
phases.
14. (Withdrawn) A system, as in claim 1, where a delay of each of one or more components  
of the electrical circuit is modeled as the sum of one or more of a constant part, a  
correlated random part, and an independent random part.
15. (Withdrawn) A system, as in claim 14, where the correlated random part of the delay of  
each component is a function of one or more common sources of variation.
16. (Withdrawn) A system, as in claim 1, where a first statistical timing analysis propagates  
timing values as a weighted sum of probability distributions of one or more of the sources  
of variation.
17. (Currently Amended) A method for incremental statistical timing analysis of an electrical  
circuit, comprising the steps of:
- a. conducting an initial statistical timing analysis and saving one or more arrival  
tightness probabilities and one or more required arrival tightness probabilities on  
each edge of a timing graph of the electrical circuit;
  - b. creating a change list based on the changes to the electrical circuit and the one  
or more statistical timing queries, and assigning levelization parameters to each  
edge of the timing graph;

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- c. conducting incremental statistical forward propagation of the arrival times and tightness probabilities on a selected edge of the timing graph;
  - d. conducting incremental statistical reverse propagation of required arrival times and required arrival tightness probabilities on a selected edge of the timing graph; and
  - e. answering the one or more statistical timing queries based on conducting the incremental statistical forward propagation and the incremental statistical reverse propagation.
18. (Original) A method, as in claim 17, where the query is one or more of: a statistical arrival time at a node, a statistical required arrival time at a node, a statistical slack at a node, a statistical slew at a node, an arrival tightness probability of an edge, a required arrival tightness probability of an edge, a criticality probability of an edge, a criticality probability of a node, and a probability of a timing test being met.
19. (Original) A method, as in claim 17, where the query requests one or more of the following: a mean, a variance, an independent random part, a sensitivity to a source of variation, a confidence level, and an entire probability distribution of a statistical timing quantity.
20. (Original) A method, as in claim 17, where the query requests a criticality of one or more paths through the electrical circuit.
21. (Original) A method, as in claim 17, where the query requests a listing of the path through the electrical circuit with the highest probability of being critical.

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22. (Original) A method, as in claim 17, where the query requests a listing of a required number of paths through the electrical circuit in order of criticality probability.
23. (Original) A method, as in claim 17, where the query requests a listing of critical paths through the electrical circuit in order of criticality probability until the sum of the criticality probabilities exceeds a required probability threshold.
24. (Original) A method, as in claim 17, where the query requests one or more of: a late mode statistical timing quantity, an early mode statistical timing quantity, a rising statistical timing quantity, and a falling statistical timing quantity.
25. (Original) A method, as in claim 17, where the change is one or more of: a removal of a wire, an addition of a wire, a buffering of a wire, a removal of a gate, an addition of a gate, a removal of a latch, an addition of a latch, a removal of a clock phase, an addition of a clock phase, and a change in the operating conditions under which timing is performed.
26. (Original) A method, as in claim 25, in which a change to the electrical circuit is the undoing of the previous change to the electrical circuit.
27. (Original) A method, as in claim 17, where the electrical circuit is one of a combinational circuit and a sequential circuit.
28. (Original) A method, as in claim 17, where the electrical circuit contains one or more of: a master-slave latch, a transparent latch, a dynamic circuit, and a flip-flop.

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29. (Original) A method, as in claim 17, where the electrical circuit has multiple clock phases.

30. (Currently Amended) A method, as in claim 17, where ~~the~~ a delay of each component of the electrical circuit is modeled as the sum of one or more of a constant part, a correlated random part, and an independent random part.

31. (Original) A method, as in claim 30, where the correlated random part of the delay of each component is a function of one or more common sources of variation.

32. (Currently Amended) A method, as in claim 17, where a first statistical timing analysis propagates timing values as a weighted sum of probability distributions of one or more of ~~the~~ sources of variation.

33. (Currently Amended) A system for incremental statistical timing analysis of an electrical circuit, comprising:

- a. means for conducting an initial statistical timing analysis and saving one or more arrival tightness and one or more required arrival tightness probabilities on each edge of a timing graph of the electrical circuit;
- b. means for creating a change list based on the changes to the electrical circuit and ~~the~~ one or more statistical timing queries, and assigning levelization parameters to each edge of the timing graph;
- c. means for conducting incremental statistical forward propagation of ~~the~~ arrival times and arrival tightness probabilities on a selected edge of the timing graph;
- d. means for conducting incremental statistical reverse propagation of required arrival times and required arrival tightness probabilities on a selected edge of the timing graph; and

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- e. means for answering the one or more statistical timing queries based on conducting the incremental statistical forward propagation and the incremental statistical reverse propagation.

34. (Currently Amended) A computer memory storing a method for incremental statistical timing analysis of an electrical circuit, the method comprising the steps of:

- a. conducting an initial statistical timing analysis and saving one or more arrival tightness probabilities and one or more required arrival tightness probabilities on each edge of a timing graph of the electrical circuit;
- b. creating a change list based on the changes to the electrical circuit and the one or more statistical timing queries, and assigning levelization parameters to each edge of the timing graph;
- c. conducting incremental statistical forward propagation of the arrival times and tightness probabilities on a selected edge of the timing graph;
- d. conducting incremental statistical reverse propagation of required arrival times and required arrival tightness probabilities on a selected edge of the timing graph; and
- e. answering the one or more statistical timing queries based on conducting the incremental statistical forward propagation and the incremental statistical reverse propagation.

35. (Currently Amended) A product output response to a query produced by a process for incremental statistical timing analysis of an integrated circuit, the process comprising the steps of:

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- a. conducting an initial statistical timing analysis and saving one or more arrival tightness probabilities and one or more required arrival tightness probabilities on each edge of a timing graph of the integrated circuit;
- b. creating a change list based on the changes to the electrical circuit and ~~the~~ one or more statistical timing queries, and assigning levelization parameters to each edge of the timing graph;
- c. conducting incremental statistical forward propagation of the arrival times and tightness probabilities on a selected edge of the timing graph;
- d. conducting incremental statistical reverse propagation of required arrival times and required arrival tightness probabilities on a selected edge of the timing graph; and
- e. providing the output response by answering the one or more statistical timing queries based on conducting the incremental statistical forward propagation and the incremental statistical reverse propagation.